Search Notes

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App	ncatioi	n/Conti	OI NO.

10/044,325 Examiner

Ricardo Pizarro

Applicant(s)/Patent	under
Reexamination	

IYER ET AL. Art Unit

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SEARCHED				
Class	Subclass	Date	Examiner	
370	395.1	10/5	W	
	387 388 288			
	254	10/6		
	255	10/5	M	
	395.33			
	201			
	230			
	352			
	353			
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
EBST	10/3	V,
EAST	10/5	M
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